AMD Xilinx - XCV1600E-7FG1156I Datasheet

Welcome to E-XFL.COM

Understanding Embedded - FPGAs (Field Programmable Gate Array)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications,

Details	
Product Status	Obsolete
Number of LABs/CLBs	7776
Number of Logic Elements/Cells	34992
Total RAM Bits	589824
Number of I/O	724
Number of Gates	2188742
Voltage - Supply	1.71V ~ 1.89V
Mounting Type	Surface Mount
Operating Temperature	-40°C ~ 100°C (TJ)
Package / Case	1156-BBGA
Supplier Device Package	1156-FBGA (35x35)
Purchase URL	https://www.e-xfl.com/product-detail/xilinx/xcv1600e-7fg1156i

Email: info@E-XFL.COM Address: Room A, 16/F, Full Win Commercial Centre, 573 Nathan Road, Mongkok, Hong Kong

Virtex™-E 1.8 V Field Programmable Gate Arrays

DS022-2 (v2.8) January 16, 2006

Production Product Specification

Architectural Description

Virtex-E Array

The Virtex-E user-programmable gate array, shown in Figure 1, comprises two major configurable elements: configurable logic blocks (CLBs) and input/output blocks (IOBs).

- CLBs provide the functional elements for constructing logic
- IOBs provide the interface between the package pins and the CLBs

CLBs interconnect through a general routing matrix (GRM). The GRM comprises an array of routing switches located at the intersections of horizontal and vertical routing channels. Each CLB nests into a VersaBlock™ that also provides local routing resources to connect the CLB to the GRM.

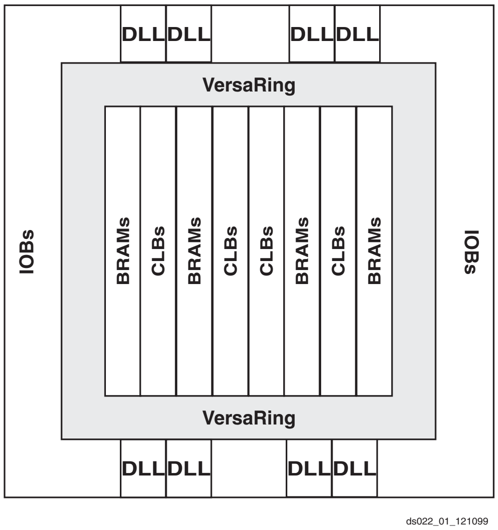


Figure 1: **Virtex-E Architecture Overview**

The VersaRing™ I/O interface provides additional routing resources around the periphery of the device. This routing improves I/O routability and facilitates pin locking.

The Virtex-E architecture also includes the following circuits that connect to the GRM.

- Dedicated block memories of 4096 bits each
- Clock DLLs for clock-distribution delay compensation and clock domain control
- 3-State buffers (BUFTs) associated with each CLB that drive dedicated segmentable horizontal routing resources

Values stored in static memory cells control the configurable logic elements and interconnect resources. These values load into the memory cells on power-up, and can reload if necessary to change the function of the device.

Input/Output Block

The Virtex-E IOB, Figure 2, features SelectI/O+ inputs and outputs that support a wide variety of I/O signalling standards, see Table 1.

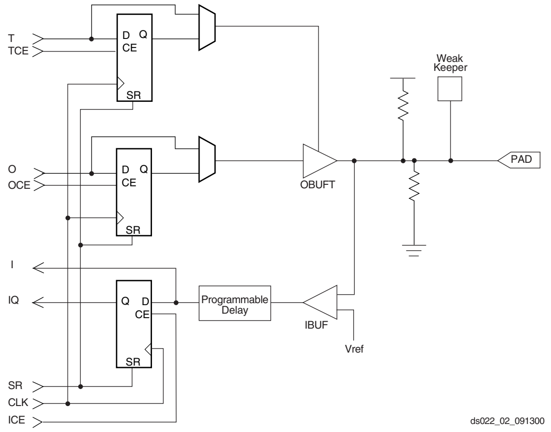


Figure 2: **Virtex-E Input/Output Block (IOB)**

The three IOB storage elements function either as edge-triggered D-type flip-flops or as level-sensitive latches. Each IOB has a clock signal (CLK) shared by the three flip-flops and independent clock enable signals for each flip-flop.

Table 1: **Supported I/O Standards**

I/O Standard	Output V_{CCO}	Input V_{CCO}	Input V_{REF}	Board Termination Voltage (V_{TT})
LVTTL	3.3	3.3	N/A	N/A
LVCMOS2	2.5	2.5	N/A	N/A
LVCMOS18	1.8	1.8	N/A	N/A
SSTL3 I & II	3.3	N/A	1.50	1.50
SSTL2 I & II	2.5	N/A	1.25	1.25
GTL	N/A	N/A	0.80	1.20
GTL+	N/A	N/A	1.0	1.50
HSTL I	1.5	N/A	0.75	0.75
HSTL III & IV	1.5	N/A	0.90	1.50
CTT	3.3	N/A	1.50	1.50
AGP-2X	3.3	N/A	1.32	N/A
PCI33_3	3.3	3.3	N/A	N/A
PCI66_3	3.3	3.3	N/A	N/A
BLVDS & LVDS	2.5	N/A	N/A	N/A
LVPECL	3.3	N/A	N/A	N/A

In addition to the CLK and CE control signals, the three flip-flops share a Set/Reset (SR). For each flip-flop, this signal can be independently configured as a synchronous Set, a synchronous Reset, an asynchronous Preset, or an asynchronous Clear.

The output buffer and all of the IOB control signals have independent polarity controls.

All pads are protected against damage from electrostatic discharge (ESD) and from over-voltage transients. After configuration, clamping diodes are connected to V_{CCO} with the exception of LVCMOS18, LVCMOS25, GTL, GTL+, LVDS, and LVPECL.

Optional pull-up, pull-down and weak-keeper circuits are attached to each pad. Prior to configuration all outputs not involved in configuration are forced into their high-impedance state. The pull-down resistors and the weak-keeper circuits are inactive, but I/Os can optionally be pulled up.

The activation of pull-up resistors prior to configuration is controlled on a global basis by the configuration mode pins. If the pull-up resistors are not activated, all the pins are in a high-impedance state. Consequently, external pull-up or pull-down resistors must be provided on pins required to be at a well-defined logic level prior to configuration.

All Virtex-E IOBs support IEEE 1149.1-compatible Boundary Scan testing.

Input Path

The Virtex-E IOB input path routes the input signal directly to internal logic and/ or through an optional input flip-flop.

An optional delay element at the D-input of this flip-flop eliminates pad-to-pad hold time. The delay is matched to the internal clock-distribution delay of the FPGA, and when used, assures that the pad-to-pad hold time is zero.

Each input buffer can be configured to conform to any of the low-voltage signalling standards supported. In some of these standards the input buffer utilizes a user-supplied threshold voltage, V_{REF}. The need to supply V_{REF} imposes constraints on which standards can be used in close proximity to each other. See **I/O Banking**.

There are optional pull-up and pull-down resistors at each user I/O input for use after configuration. Their value is in the range 50 – 100 kΩ.

Output Path

The output path includes a 3-state output buffer that drives the output signal onto the pad. The output signal can be routed to the buffer directly from the internal logic or through an optional IOB output flip-flop.

The 3-state control of the output can also be routed directly from the internal logic or through a flip-flip that provides synchronous enable and disable.

Each output driver can be individually programmed for a wide range of low-voltage signalling standards. Each output buffer can source up to 24 mA and sink up to 48 mA. Drive strength and slew rate controls minimize bus transients.

In most signalling standards, the output High voltage depends on an externally supplied V_{CCO} voltage. The need to supply V_{CCO} imposes constraints on which standards can be used in close proximity to each other. See **I/O Banking**.

An optional weak-keeper circuit is connected to each output. When selected, the circuit monitors the voltage on the pad and weakly drives the pin High or Low to match the input signal. If the pin is connected to a multiple-source signal, the weak keeper holds the signal in its last state if all drivers are disabled. Maintaining a valid logic level in this way eliminates bus chatter.

Since the weak-keeper circuit uses the IOB input buffer to monitor the input level, an appropriate V_{REF} voltage must be provided if the signalling standard requires one. The provision of this voltage must comply with the I/O banking rules.

I/O Banking

Some of the I/O standards described above require V_{CCO} and/or V_{REF} voltages. These voltages are externally supplied and connected to device pins that serve groups of IOBs, called banks. Consequently, restrictions exist about which I/O standards can be combined within a given bank.

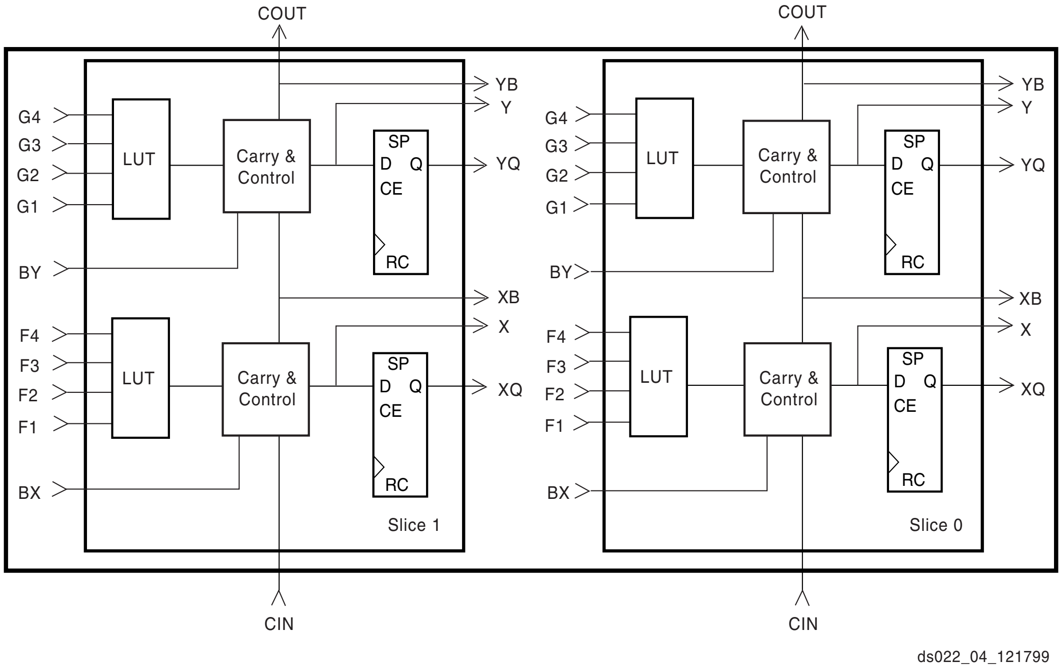


Figure 4: **2-Slice Virtex-E CLB**

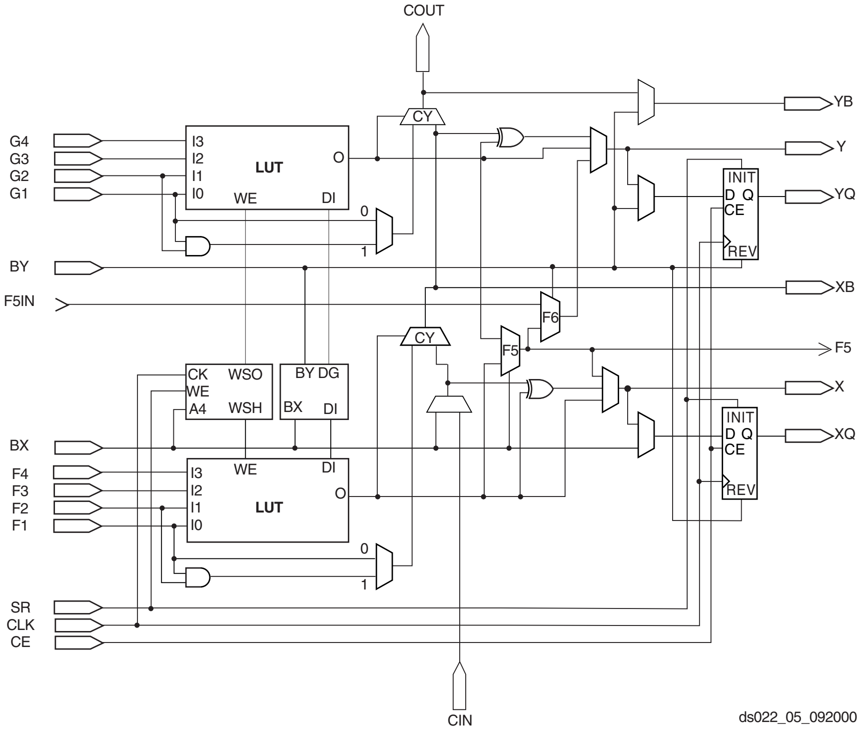


Figure 5: **Detailed View of Virtex-E Slice**

Storage Elements

The storage elements in the Virtex-E slice can be configured either as edge-triggered D-type flip-flops or as level-sensitive latches. The D inputs can be driven either by the function generators within the slice or directly from slice inputs, bypassing the function generators.

In addition to Clock and Clock Enable signals, each Slice has synchronous set and reset signals (SR and BY). SR

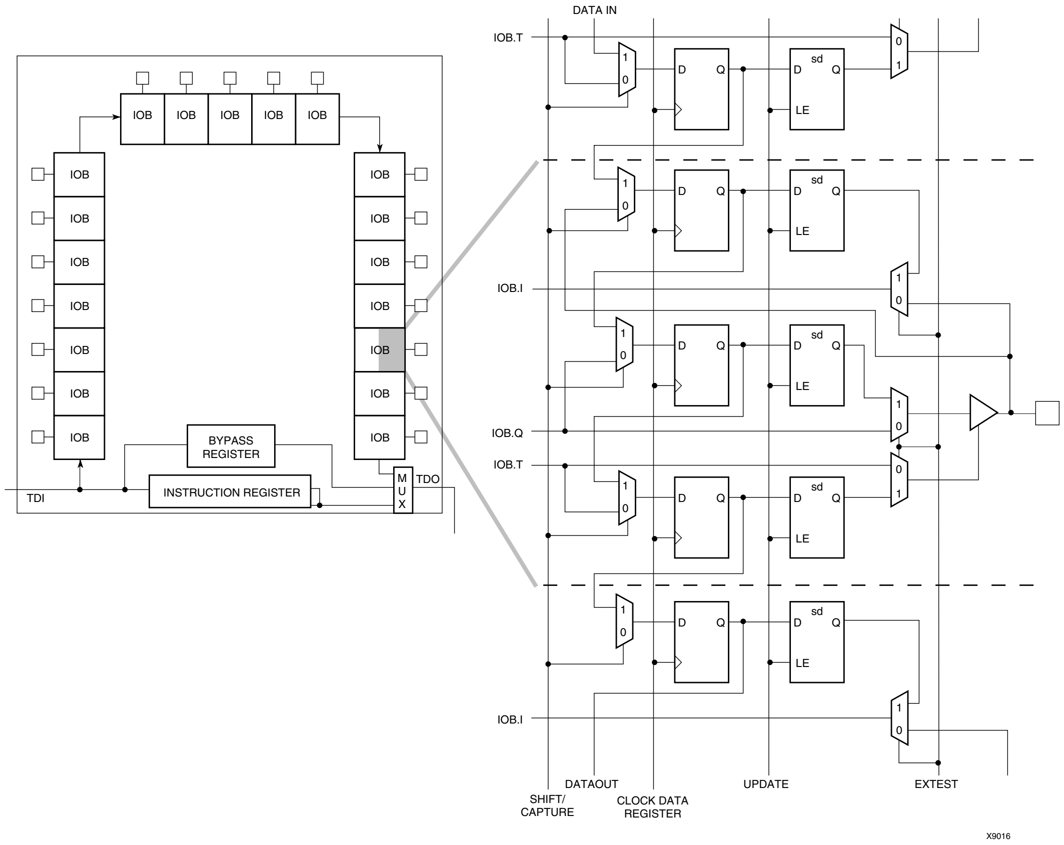


Figure 11: **Virtex-E Family Boundary Scan Logic**

Instruction Set

The Virtex-E series Boundary Scan instruction set also includes instructions to configure the device and read back configuration data (CFG_IN, CFG_OUT, and JSTART). The complete instruction set is coded as shown in Table 6..

Table 6: **Boundary Scan Instructions**

Boundary Scan Command	Binary Code(4:0)	Description
EXTEST	00000	Enables Boundary Scan EXTEST operation
SAMPLE/ PRELOAD	00001	Enables Boundary Scan SAMPLE/PRELOAD operation
USER1	00010	Access user-defined register 1
USER2	00011	Access user-defined register 2
CFG_OUT	00100	Access the configuration bus for read operations.
CFG_IN	00101	Access the configuration bus for write operations.
INTEST	00111	Enables Boundary Scan INTEST operation
USERCODE	01000	Enables shifting out USER code
IDCODE	01001	Enables shifting out of ID Code
HIGHZ	01010	3-states output pins while enabling the Bypass Register
JSTART	01100	Clock the start-up sequence when StartupClk is TCK
BYPASS	11111	Enables BYPASS
RESERVED	All other codes	Xilinx reserved instructions

the internal storage elements to begin changing state in response to the logic and the user clock.

The relative timing of these events can be changed. In addition, the GTS, GSR, and GWE events can be made dependent on the DONE pins of multiple devices all going High, forcing the devices to start synchronously. The sequence can also be paused at any stage until lock has been achieved on any or all DLLs.

Readback

The configuration data stored in the Virtex-E configuration memory can be readback for verification. Along with the configuration data it is possible to readback the contents all flip-flops/latches, LUT RAMs, and block RAMs. This capability is used for real-time debugging. For more detailed information, see application note XAPP138 "Virtex FPGA Series Configuration and Readback".

Design Considerations

This section contains more detailed design information on the following features.

- Delay-Locked Loop . . . see page 19
- BlockRAM . . . see page 24
- SelectI/O . . . see page 31

Using DLLs

The Virtex-E FPGA series provides up to eight fully digital dedicated on-chip Delay-Locked Loop (DLL) circuits which provide zero propagation delay, low clock skew between output clock signals distributed throughout the device, and advanced clock domain control. These dedicated DLLs can be used to implement several circuits which improve and simplify system level design.

Introduction

As FPGAs grow in size, quality on-chip clock distribution becomes increasingly important. Clock skew and clock delay impact device performance and the task of managing clock skew and clock delay with conventional clock trees becomes more difficult in large devices. The Virtex-E series of devices resolve this potential problem by providing up to eight fully digital dedicated on-chip DLL circuits, which provide zero propagation delay and low clock skew between output clock signals distributed throughout the device.

Each DLL can drive up to two global clock routing networks within the device. The global clock distribution network minimizes clock skews due to loading differences. By monitoring a sample of the DLL output clock, the DLL can compensate for the delay on the routing network, effectively eliminating the delay from the external input port to the individual clock loads within the device.

In addition to providing zero delay with respect to a user source clock, the DLL can provide multiple phases of the source clock. The DLL can also act as a clock doubler or it can divide the user source clock by up to 16.

Clock multiplication gives the designer a number of design alternatives. For instance, a 50 MHz source clock doubled by the DLL can drive an FPGA design operating at 100 MHz. This technique can simplify board design because the clock path on the board no longer distributes such a high-speed signal. A multiplied clock also provides designers the option of time-domain-multiplexing, using one circuit twice per clock cycle, consuming less area than two copies of the same circuit. Two DLLs in can be connected in series to increase the effective clock multiplication factor to four.

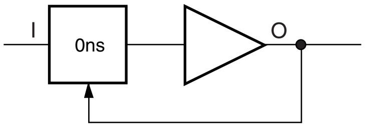
The DLL can also act as a clock mirror. By driving the DLL output off-chip and then back in again, the DLL can be used to deskew a board level clock between multiple devices.

In order to guarantee the system clock establishes prior to the device "waking up," the DLL can delay the completion of the device configuration process until after the DLL achieves lock.

By taking advantage of the DLL to remove on-chip clock delay, the designer can greatly simplify and improve system level design involving high-fanout, high-performance clocks.

Library DLL Symbols

Figure 21 shows the simplified Xilinx library DLL macro symbol, BUFGDLL. This macro delivers a quick and efficient way to provide a system clock with zero propagation delay throughout the device. Figure 22 and Figure 23 show the two library DLL primitives. These symbols provide access to the complete set of DLL features when implementing more complex applications.



ds022_25_121099

Figure 21: **Simplified DLL Macro Symbol BUFGDLL**

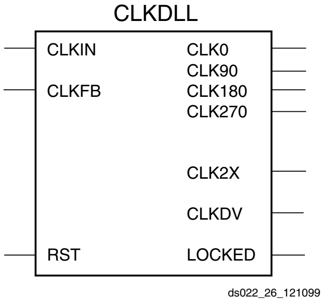


Figure 22: **Standard DLL Symbol CLKDLL**

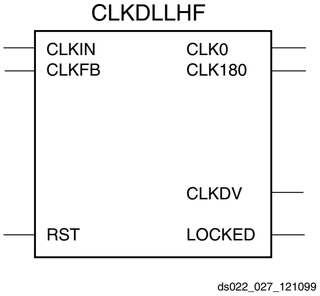


Figure 23: **High Frequency DLL Symbol CLKDLLHF**

BUFGDLL Pin Descriptions

Use the BUFGDLL macro as the simplest way to provide zero propagation delay for a high-fanout on-chip clock from an external input. This macro uses the IBUFG, CLKDLL and BUFG primitives to implement the most basic DLL application as shown in Figure 24.

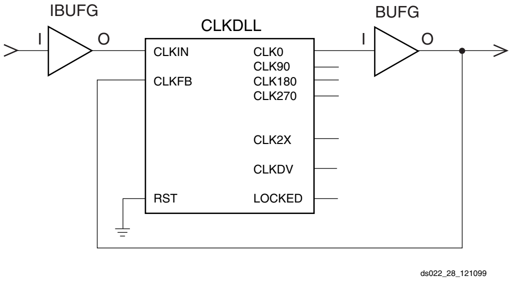


Figure 24: **BUFGDLL Schematic**

This symbol does not provide access to the advanced clock domain controls or to the clock multiplication or clock division features of the DLL. This symbol also does not provide access to the RST, or LOCKED pins of the DLL. For access to these features, a designer must use the library DLL primitives described in the following sections.

Source Clock Input — I

The I pin provides the user source clock, the clock signal on which the DLL operates, to the BUFGDLL. For the BUFGDLL macro the source clock frequency must fall in the low frequency range as specified in the data sheet. The BUFGDLL requires an external signal source clock. Therefore, only an external input port can source the signal that drives the BUFGDLL I pin.

Clock Output — O

The clock output pin O represents a delay-compensated version of the source clock (I) signal. This signal, sourced by a global clock buffer BUFG symbol, takes advantage of the dedicated global clock routing resources of the device.

The output clock has a 50-50 duty cycle unless you deactivate the duty cycle correction property.

CLKDLL Primitive Pin Descriptions

The library CLKDLL primitives provide access to the complete set of DLL features needed when implementing more complex applications with the DLL.

Source Clock Input — CLKIN

The CLKIN pin provides the user source clock (the clock signal on which the DLL operates) to the DLL. The CLKIN frequency must fall in the ranges specified in the data sheet. A global clock buffer (BUFG) driven from another CLKDLL, one of the global clock input buffers (IBUFG), or an IO_LVDS_DLL pin on the same edge of the device (top or bottom) must source this clock signal. There are four IO_LVDS_DLL input pins that can be used as inputs to the DLLs. This makes a total of eight usable input pins for DLLs in the Virtex-E family.

Feedback Clock Input — CLKFB

The DLL requires a reference or feedback signal to provide the delay-compensated output. Connect only the CLK0 or CLK2X DLL outputs to the feedback clock input (CLKFB) pin to provide the necessary feedback to the DLL. The feedback clock input can also be provided through one of the following pins.

IBUFG - Global Clock Input Pad

IO_LVDS_DLL - the pin adjacent to IBUFG

If an IBUFG sources the CLKFB pin, the following special rules apply.

1. An external input port must source the signal that drives the IBUFG I pin.
2. The CLK2X output must feedback to the device if both the CLK0 and CLK2X outputs are driving off chip devices.
3. That signal must directly drive only OBUFs and nothing else.

These rules enable the software determine which DLL clock output sources the CLKFB pin.

Reset Input — RST

When the reset pin RST activates the LOCKED signal deactivates within four source clock cycles. The RST pin, active High, must either connect to a dynamic signal or tied to

Because any single DLL can access only two BUFGs at most, any additional output clock signals must be routed from the DLL in this example on the high speed backbone routing.

The dll_2x files in the xapp132.zip file show the VHDL and Verilog implementation of this circuit.

Virtex-E 4x Clock

Two DLLs located in the same half-edge (top-left, top-right, bottom-right, bottom-left) can be connected together, without using a BUFG between the CLKDLLs, to generate a 4x clock as shown in Figure 30. Virtex-E devices, like the Virtex devices, have four clock networks that are available for internal deskewing of the clock. Each of the eight DLLs have access to two of the four clock networks. Although all the DLLs can be used for internal deskewing, the presence of two GCLKBUFs on the top and two on the bottom indicate that only two of the four DLLs on the top (and two of the four DLLs on the bottom) can be used for this purpose.

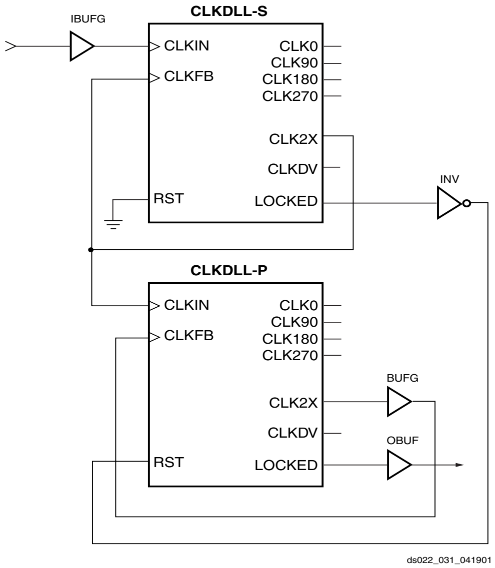


Figure 30: **DLL Generation of 4x Clock in Virtex-E Devices**

The dll_4xe files in the xapp132.zip file show the DLL implementation in Verilog for Virtex-E devices. These files can be found at:

ftp://ftp.xilinx.com/pub/applications/xapp/xapp132.zip

Using Block SelectRAM+ Features

The Virtex FPGA Series provides dedicated blocks of on-chip, true dual-read/write port synchronous RAM, with 4096 memory cells. Each port of the block SelectRAM+ memory can be independently configured as a read/write port, a read port, a write port, and can be configured to a specific data width. The block SelectRAM+ memory offers new capabilities allowing the FPGA designer to simplify designs.

Operating Modes

VIrtex-E block SelectRAM+ memory supports two operating modes:

- Read Through
- Write Back

Read Through (one clock edge)

The read address is registered on the read port clock edge and data appears on the output after the RAM access time. Some memories might place the latch/register at the outputs, depending on whether a faster clock-to-out versus set-up time is desired. This is generally considered to be an inferior solution, since it changes the read operation to an asynchronous function with the possibility of missing an address/control line transition during the generation of the read pulse clock.

Write Back (one clock edge)

The write address is registered on the write port clock edge and the data input is written to the memory and mirrored on the output.

Block SelectRAM+ Characteristics

- All inputs are registered with the port clock and have a set-up to clock timing specification.
- All outputs have a read through or write back function depending on the state of the port WE pin. The outputs relative to the port clock are available after the clock-to-out timing specification.
- The block SelectRAMs are true SRAM memories and do not have a combinatorial path from the address to the output. The LUT SelectRAM+ cells in the CLBs are still available with this function.
- The ports are completely independent from each other (*i.e.,* clocking, control, address, read/write function, and data width) without arbitration.
- A write operation requires only one clock edge.
- A read operation requires only one clock edge.

The output ports are latched with a self timed circuit to guarantee a glitch free read. The state of the output port does not change until the port executes another read or write operation.

Library Primitives

Figure 31 and Figure 32 show the two generic library block SelectRAM+ primitives. Table 14 describes all of the available primitives for synthesis and simulation.

The voltage reference signal is "banked" within the Virtex-E device on a half-edge basis such that for all packages there are eight independent V_{REF} banks internally. See Figure 38 for a representation of the Virtex-E I/O banks. Within each bank approximately one of every six I/O pins is automatically configured as a V_{REF} input. After placing a differential amplifier input signal within a given V_{REF} bank, the same external source must drive all I/O pins configured as a V_{REF} input.

IBUF placement restrictions require that any differential amplifier input signals within a bank be of the same standard. How to specify a specific location for the IBUF via the LOC property is described below. Table 19 summarizes the Virtex-E input standards compatibility requirements.

An optional delay element is associated with each IBUF. When the IBUF drives a flip-flop within the IOB, the delay element by default activates to ensure a zero hold-time requirement. The NODELAY=TRUE property overrides this default.

When the IBUF does not drive a flip-flop within the IOB, the delay element de-activates by default to provide higher performance. To delay the input signal, activate the delay element with the DELAY=TRUE property.

Table 19: **Xilinx Input Standards Compatibility Requirements**

Rule 1	Standards with the same input V_{CCO}, output V_{CCO}, and V_{REF} can be placed within the same bank.

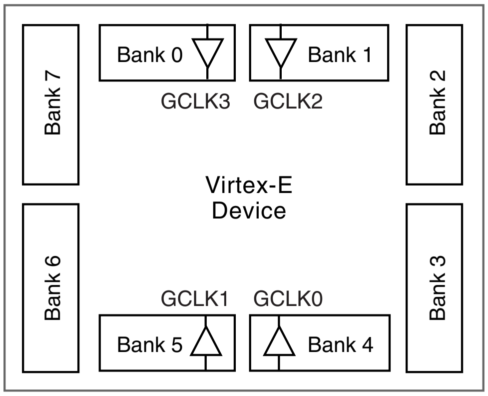


Figure 38: **Virtex-E I/O Banks**

IBUFG

Signals used as high fanout clock inputs to the Virtex-E device should drive a global clock input buffer (IBUFG) via an external input port in order to take advantage of one of the four dedicated global clock distribution networks. The output of the IBUFG should only drive a CLKDLL, CLKDLLHF, or BUFG symbol. The generic Virtex-E IBUFG symbol appears in Figure 39.

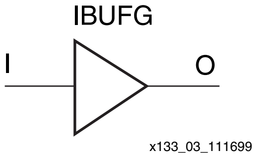


Figure 39: **Virtex-E Global Clock Input Buffer (IBUFG) Symbol**

The extension to the base name determines which I/O standard is used by the IBUFG. With no extension specified for the generic IBUFG symbol, the assumed standard is LVTTL.

The following list details variations of the IBUFG symbol.

- IBUFG
- IBUFG_LVCMOS2
- IBUFG_PCI33_3
- IBUFG_PCI66_3
- IBUFG_GTL
- IBUFG_GTLP
- IBUFG_HSTL_I
- IBUFG_HSTL_III
- IBUFG_HSTL_IV
- IBUFG_SSTL3_I
- IBUFG_SSTL3_II
- IBUFG_SSTL2_I
- IBUFG_SSTL2_II
- IBUFG_CTT
- IBUFG_AGP
- IBUFG_LVCMOS18
- IBUFG_LVDS
- IBUFG_LVPECL

When the IBUFG symbol supports an I/O standard that requires a differential amplifier input, the IBUFG automatically configures as a differential amplifier input buffer. The low-voltage I/O standards with a differential amplifier input require an external reference voltage input V_{REF}.

The voltage reference signal is "banked" within the Virtex-E device on a half-edge basis such that for all packages there are eight independent V_{REF} banks internally. See Figure 38 for a representation of the Virtex-E I/O banks. Within each bank approximately one of every six I/O pins is automatically configured as a V_{REF} input. After placing a differential amplifier input signal within a given V_{REF} bank, the same external source must drive all I/O pins configured as a V_{REF} input.

IBUFG placement restrictions require any differential amplifier input signals within a bank be of the same standard. The LOC property can specify a location for the IBUFG.

As an added convenience, the BUFGP can be used to instantiate a high fanout clock input. The BUFGP symbol

IOB Flip-Flop/Latch Property

The Virtex-E series I/O Block (IOB) includes an optional register on the input path, an optional register on the output path, and an optional register on the 3-state control pin. The design implementation software automatically takes advantage of these registers when the following option for the Map program is specified.

map –pr b <filename>

Alternatively, the IOB = TRUE property can be placed on a register to force the mapper to place the register in an IOB.

Location Constraints

Specify the location of each SelectI/O symbol with the location constraint LOC attached to the SelectI/O symbol. The external port identifier indicates the value of the location constrain. The format of the port identifier depends on the package chosen for the specific design.

The LOC properties use the following form:

LOC=A42

LOC=P37

Output Slew Rate Property

As mentioned above, a variety of symbol names provide the option of choosing the desired slew rate for the output buffers. In the case of the LVTTL output buffers (OBUF, OBUFT, and IOBUF), slew rate control can be alternatively programed with the SLEW= property. By default, the slew rate for each output buffer is reduced to minimize power bus transients when switching non-critical signals. The SLEW= property has one of the two following values.

SLEW=SLOW

SLEW=FAST

Output Drive Strength Property

The desired output drive strength can be additionally specified by choosing the appropriate library symbol. The Xilinx library also provides an alternative method for specifying this feature. For the LVTTL output buffers (OBUF, OBUFT, and IOBUF, the desired drive strength can be specified with the DRIVE= property. This property could have one of the following seven values.

DRIVE=2
DRIVE=4
DRIVE=6
DRIVE=8
DRIVE=12 (Default)
DRIVE=16
DRIVE=24

Design Considerations

Reference Voltage (V_{REF}) Pins

Low-voltage I/O standards with a differential amplifier input buffer require an input reference voltage (V_{REF}). Provide the V_{REF} as an external signal to the device.

The voltage reference signal is "banked" within the device on a half-edge basis such that for all packages there are eight independent V_{REF} banks internally. See Figure 38 for a representation of the Virtex-E I/O banks. Within each bank approximately one of every six I/O pins is automatically configured as a V_{REF} input. After placing a differential amplifier input signal within a given V_{REF} bank, the same external source must drive all I/O pins configured as a V_{REF} input.

Within each V_{REF} bank, any input buffers that require a V_{REF} signal must be of the same type. Output buffers of any type and input buffers can be placed without requiring a reference voltage within the same V_{REF} bank.

Output Drive Source Voltage (V_{CCO}) Pins

Many of the low voltage I/O standards supported by SelectI/O devices require a different output drive source voltage (V_{CCO}). As a result each device can often have to support multiple output drive source voltages.

The Virtex-E series supports eight banks for the HQ and PQ packages. The CS package supports four V_{CCO} banks.

Output buffers within a given V_{CCO} bank must share the same output drive source voltage. Input buffers for LVTTL, LVCMOS2, LVCMOS18, PCI33_3, and PCI 66_3 use the V_{CCO} voltage for Input V_{CCO} voltage.

Transmission Line Effects

The delay of an electrical signal along a wire is dominated by the rise and fall times when the signal travels a short distance. Transmission line delays vary with inductance and capacitance, but a well-designed board can experience delays of approximately 180 ps per inch.

Transmission line effects, or reflections, typically start at 1.5" for fast (1.5 ns) rise and fall times. Poor (or non-existent) termination or changes in the transmission line impedance cause these reflections and can cause additional delay in longer traces. As system speeds continue to increase, the effect of I/O delays can become a limiting factor and therefore transmission line termination becomes increasingly more important.

Termination Techniques

A variety of termination techniques reduce the impact of transmission line effects.

The following are output termination techniques:

- None
- Series
- Parallel (Shunt)
- Series and Parallel (Series-Shunt)

Input termination techniques include the following.

- None
- Parallel (Shunt)

These termination techniques can be applied in any combination. A generic example of each combination of termination methods appears in Figure 43.

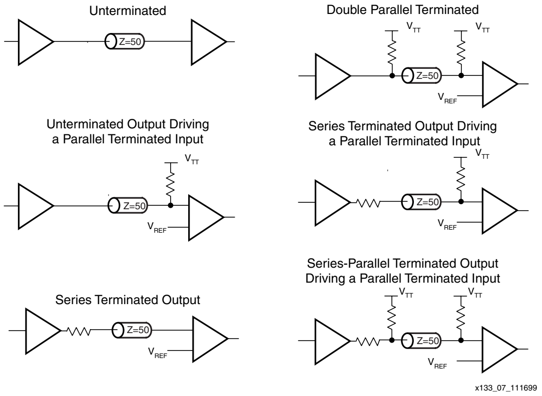


Figure 43: **Overview of Standard Input and Output Termination Methods**

Simultaneous Switching Guidelines

Ground bounce can occur with high-speed digital ICs when multiple outputs change states simultaneously, causing undesired transient behavior on an output, or in the internal logic. This problem is also referred to as the Simultaneous Switching Output (SSO) problem.

Ground bounce is primarily due to current changes in the combined inductance of ground pins, bond wires, and ground metallization. The IC internal ground level deviates from the external system ground level for a short duration (a few nanoseconds) after multiple outputs change state simultaneously.

Ground bounce affects stable Low outputs and all inputs because they interpret the incoming signal by comparing it to the internal ground. If the ground bounce amplitude exceeds the actual instantaneous noise margin, then a non-changing input can be interpreted as a short pulse with a polarity opposite to the ground bounce.

Table 21 provides guidelines for the maximum number of simultaneously switching outputs allowed per output power/ground pair to avoid the effects of ground bounce. See Table 22 for the number of effective output power/ground pairs for each Virtex-E device and package combination.

Table 21: **Guidelines for Max Number of Simultaneously Switching Outputs per Power/Ground Pair**

Standard	Package		
	BGA, CS, FGA	**HQ**	**PQ, TQ**
LVTTL Slow Slew Rate, 2 mA drive	68	49	36
LVTTL Slow Slew Rate, 4 mA drive	41	31	20
LVTTL Slow Slew Rate, 6 mA drive	29	22	15
LVTTL Slow Slew Rate, 8 mA drive	22	17	12
LVTTL Slow Slew Rate, 12 mA drive	17	12	9
LVTTL Slow Slew Rate, 16 mA drive	14	10	7
LVTTL Slow Slew Rate, 24 mA drive	9	7	5
LVTTL Fast Slew Rate, 2 mA drive	40	29	21
LVTTL Fast Slew Rate, 4 mA drive	24	18	12
LVTTL Fast Slew Rate, 6 mA drive	17	13	9
LVTTL Fast Slew Rate, 8 mA drive	13	10	7
LVTTL Fast Slew Rate, 12 mA drive	10	7	5
LVTTL Fast Slew Rate, 16 mA drive	8	6	4
LVTTL Fast Slew Rate, 24 mA drive	5	4	3
LVCMOS	10	7	5
PCI	8	6	4
GTL	4	4	4
GTL+	4	4	4

Global Clock Input to Output Delay for LVTTL, 12 mA, Fast Slew Rate, *without* DLL

Description[1]	Symbol	Device	Speed Grade[2]				Units
			Min	-8	-7	-6	
LVTTL Global Clock Input to Output Delay using Output Flip-flop, 12 mA, Fast Slew Rate, *without* DLL. For data *output* with different standards, adjust the delays with the values shown in **IOB Output Switching Characteristics Standard Adjustments**, page 10.	T_{ICKOF}	XCV50E	1.5	4.2	4.4	4.6	ns
		XCV100E	1.5	4.2	4.4	4.6	ns
		XCV200E	1.5	4.3	4.5	4.7	ns
		XCV300E	1.5	4.3	4.5	4.7	ns
		XCV400E	1.5	4.4	4.6	4.8	ns
		XCV600E	1.6	4.5	4.7	4.9	ns
		XCV1000E	1.7	4.6	4.8	5.0	ns
		XCV1600E	1.8	4.7	4.9	5.1	ns
		XCV2000E	1.8	4.8	5.0	5.2	ns
		XCV2600E	2.0	5.0	5.2	5.4	ns
		XCV3200E	2.2	5.2	5.4	5.6	ns

Notes:

1. Listed above are representative values where one global clock input drives one vertical clock line in each accessible column, and where all accessible IOB and CLB flip-flops are clocked by the global clock net.
2. Output timing is measured at 50% V_{CC} threshold with 35 pF external capacitive load. For other I/O standards and different loads, see Table 3 and Table 4.

Global Clock Set-Up and Hold for LVTTL Standard, *without* DLL

Description[1]	Symbol	Device	Speed Grade[2, 3]				Units
			Min	-8	-7	-6	
Input Setup and Hold Time Relative to Global Clock Input Signal for LVTTL Standard. For data input with different standards, adjust the setup time delay by the values shown in **IOB Input Switching Characteristics Standard Adjustments**, page 8.							
Full Delay Global Clock and IFF, without DLL	T_{PSFD}/T_{PHFD}	XCV50E	1.8 / 0	1.8 / 0	1.8 / 0	1.8 / 0	ns
		XCV100E	1.8 / 0	1.8 / 0	1.8 / 0	1.8 / 0	ns
		XCV200E	1.9 / 0	1.9 / 0	1.9 / 0	1.9 / 0	ns
		XCV300E	2.0 / 0	2.0 / 0	2.0 / 0	2.0 / 0	ns
		XCV400E	2.0 / 0	2.0 / 0	2.0 / 0	2.0 / 0	ns
		XCV600E	2.1 / 0	2.1 / 0	2.1 / 0	2.1 / 0	ns
		XCV1000E	2.3 / 0	2.3 / 0	2.3 / 0	2.3 / 0	ns
		XCV1600E	2.5 / 0	2.5 / 0	2.5 / 0	2.5 / 0	ns
		XCV2000E	2.5 / 0	2.5 / 0	2.5 / 0	2.5 / 0	ns
		XCV2600E	2.7 / 0	2.7 / 0	2.7 / 0	2.7 / 0	ns
		XCV3200E	2.8 / 0	2.8 / 0	2.8 / 0	2.8 / 0	ns

Notes:

1. IFF = Input Flip-Flop or Latch
2. Setup time is measured relative to the Global Clock input signal with the fastest route and the lightest load. Hold time is measured relative to the Global Clock input signal with the slowest route and heaviest load.
3. A Zero “0” Hold Time listing indicates no hold time or a negative hold time. Negative values can not be guaranteed “best-case”, but if a “0” is listed, there is no positive hold time.

DLL Timing Parameters

All devices are 100 percent functionally tested. Because of the difficulty in directly measuring many internal timing parameters, those parameters are derived from benchmark timing patterns. The following guidelines reflect worst-case values across the recommended operating conditions.

Description	Symbol	F_{CLKIN}	Speed Grade						Units
			-8		-7		-6		
			Min	Max	Min	Max	Min	Max	
Input Clock Frequency (CLKDLLHF)	FCLKINHF		60	350	60	320	60	275	MHz
Input Clock Frequency (CLKDLL)	FCLKINLF		25	160	25	160	25	135	MHz
Input Clock Low/High Pulse Width	T_{DLLPW}	≥2□5 MHz	5.0		5.0		5.0		ns
		≥□50 MHz	3.0		3.0		3.0		ns
		≥100 MHz	2.4		2.4		2.4		ns
		≥□150 MHz	2.0		2.0		2.0		ns
		≥□200 MHz	1.8		1.8		1.8		ns
		≥□250 MHz	1.5		1.5		1.5		ns
		≥□300 MHz	1.3		1.3		NA		ns

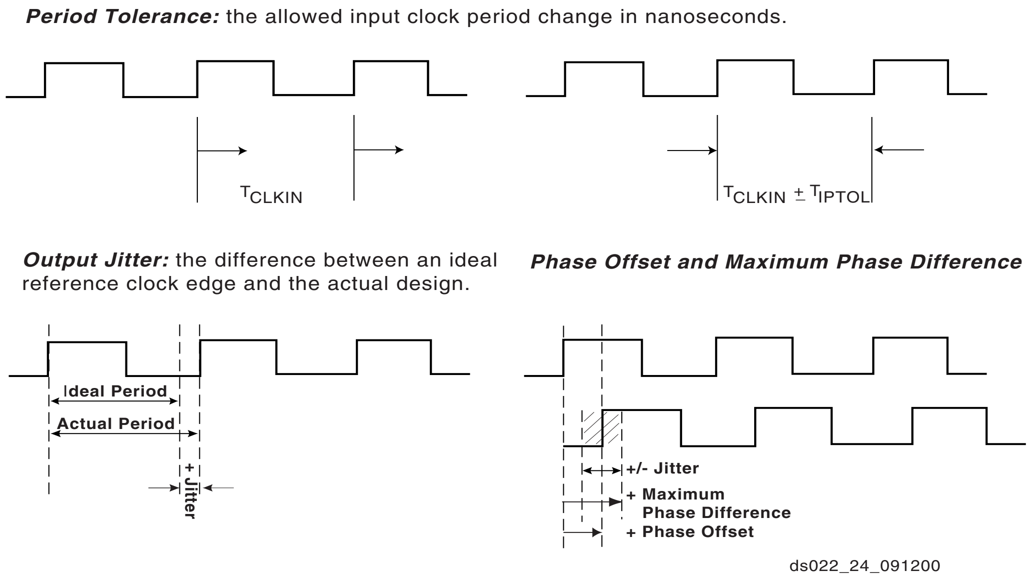


Figure 4: **DLL Timing Waveforms**

Table 8: **HQ240 — XCV600E, XCV1000E**

Pin #	Pin Description	Bank
P138	IO_D5_L26N_YY	3
P137	VCCINT	NA
P136	VCCO	3
P135	GND	NA
P134	IO_D6_L27P_Y	3
P133	IO_VREF_L27N_Y	3
P132	IO_VREF	3
P131	IO_L28P_Y	3
P130	IO_VREF_L28N_Y	3
P129	GND	NA
P128	IO_L29P_Y	3
P127	IO_L29N_Y	3
P126	IO_VREF_L30P_Y	3
P125	IO_L30N_Y	3
P124	IO_D7_L31P_YY	3
P123	IO_INIT_L31N_YY	3
P122	PROGRAM	NA
P121	VCCO	3
P120	DONE	3
P119	GND	NA
P118	IO_L32P_YY	4
P117	IO_L32N_YY	4
P116	VCCO	4
P115	IO_VREF	4
P114	IO_L33P_YY	4
P113	IO_L33N_YY	4
P112	GND	NA
P111	IO_VREF_L34P_YY	4
P110	IO_L34N_YY	4
P109	IO_VREF	4
P108	IO_VREF_L35P_YY	4
P107	IO_L35N_YY	4
P106	GND	NA
P105	VCCO	4
P104	VCCINT	NA
P103	IO_L36P_YY	4

Table 8: **HQ240 — XCV600E, XCV1000E**

Pin #	Pin Description	Bank
P102	IO_L36N_YY	4
P101[1]	IO_VREF	4
P100	IO_L37P_Y	4
P99	IO_L37N_Y	4
P98	GND	NA
P97	IO_VREF_L38P_Y	4
P96	IO_L38N_Y	4
P95	IO_L39P	4
P94	IO_VREF_L39N	4
P93	IO_LVDS_DLL_L40P	4
P92	GCK0	4
P91	GND	NA
P90	VCCO	4
P89	GCK1	5
P88	VCCINT	NA
P87	IO_LVDS_DLL_L40N	5
P86	IO_VREF	5
P85	VCCO	5
P84	IO_VREF_L41P	5
P83	GND	NA
P82	IO_L41N	5
P81	IO	5
P80[1]	IO_VREF	5
P79	IO_L42P_YY	5
P78	IO_L42N_YY	5
P77	VCCINT	NA
P76	VCCO	5
P75	GND	NA
P74	IO_L43P_YY	5
P73	IO_VREF_L43N_YY	5
P72	IO_VREF	5
P71	IO_L44P_YY	5
P70	IO_VREF_L44N_YY	5
P69	GND	NA
P68	IO_L45P_YY	5
P67	IO_L45N_YY	5

Table 12: **BG432 — XCV300E, XCV400E, XCV600E**

Bank	Pin Description	Pin #
4	IO_L70N_Y	AK4
4	IO_L71P_YY	AJ5
4	IO_L71N_YY	AH6
4	IO_VREF_L72P_YY	AL4
4	IO_L72N_YY	AK5
4	IO_L73P_Y	AJ6
4	IO_L73N_Y	AH7
4	IO_L74P_YY	AL5
4	IO_L74N_YY	AK6
4	IO_VREF_L75P_YY	AJ7
4	IO_L75N_YY	AL6
4	IO_L76P_Y	AH9
4	IO_L76N_Y	AJ8
4	IO_VREF_L77P_Y	AK8[1]
4	IO_L77N_Y	AJ9
4	IO_VREF_L78P_YY	AL8
4	IO_L78N_YY	AK9
4	IO_L79P_YY	AK10
4	IO_L79N_YY	AL10
4	IO_L80P_YY	AH12
4	IO_L80N_YY	AK11
4	IO_L81P_YY	AJ12
4	IO_L81N_YY	AK12
4	IO_L82P_YY	AH13
4	IO_L82N_YY	AJ13
4	IO_VREF_L83P_YY	AL13
4	IO_L83N_YY	AK14
4	IO_L84P_Y	AH14
4	IO_L84N_Y	AJ14
4	IO_VREF_L85P_Y	AK15[2]
4	IO_L85N_Y	AJ15
4	IO_LVDS_DLL_L86P	AH15
5	GCK1	AK16
5	IO	AH20
5	IO	AJ19
5	IO	AJ23
5	IO	AJ24
5	IO_LVDS_DLL_L86N	AL17
5	IO_L87P_Y	AK17
5	IO_VREF_L87N_Y	AJ17[2]
5	IO_L88P_Y	AH17
5	IO_L88N_Y	AK18
5	IO_L89P_YY	AL19
5	IO_VREF_L89N_YY	AJ18
5	IO_L90P_YY	AH18
5	IO_L90N_YY	AL20
5	IO_L91P_YY	AK20
5	IO_L91N_YY	AH19
5	IO_L92P_YY	AJ20
5	IO_L92N_YY	AK21
5	IO_L93P_YY	AJ21
5	IO_L93N_YY	AL22
5	IO_L94P_YY	AJ22
5	IO_VREF_L94N_YY	AK23
5	IO_L95P_Y	AH22
5	IO_VREF_L95N_Y	AL24[1]
5	IO_L96P_Y	AK24
5	IO_L96N_Y	AH23
5	IO_L97P_YY	AK25
5	IO_VREF_L97N_YY	AJ25
5	IO_L98P_YY	AL26
5	IO_L98N_YY	AK26
5	IO_L99P_Y	AH25
5	IO_L99N_Y	AL27
5	IO_L100P_YY	AJ26
5	IO_VREF_L100N_YY	AK27
5	IO_L101P_YY	AH26
5	IO_L101N_YY	AL28
5	IO_L102P_Y	AJ27
5	IO_L102N_Y	AK28

Table 13: **BG432 Differential Pin Pair Summary XCV300E, XCV400E, XC600E**

Pair	Bank	P Pin	N Pin	AO	Other Functions
112	6	AB29	AB28	√	VREF
113	6	AA29	AB31	√	-
114	6	Y29	Y28	4	-
115	6	Y31	Y30	1	-
116	6	W30	W29	1	-
117	6	V29	V28	√	VREF
118	6	U29	V30	4	-
119	6	U30	U28	1	VREF
120	7	R29	T31	√	-
121	7	R31	R30	1	VREF
122	7	P28	P29	4	-
123	7	N30	P30	√	VREF
124	7	N31	N28	1	-
125	7	M28	M29	1	-
126	7	L30	M30	4	-
127	7	K30	K31	√	-
128	7	J30	K28	√	VREF
129	7	J28	J29	1	VREF
130	7	G30	H30	4	-
131	7	F31	H28	√	VREF
132	7	G28	G29	1	-
133	7	E30	E31	5	-
134	7	F28	F29	1	VREF
135	7	D30	D31	4	-
136	7	E28	E29	3	-

Notes:

1. AO in the XCV300E, 600E.
2. AO in the XCV300E.
3. AO in the XCV400E, 600E.
4. AO in the XCV300E, 400E.
5. AO in the XCV600E.

BG560 Ball Grid Array Packages

XCV1000E, XCV1600E, and XCV2000E devices in BG560 Ball Grid Array packages have footprint compatibility. Pins labeled I0_VREF can be used as either in all parts unless device-dependent as indicated in the footnotes. If the pin is not used as V_{REF}, it can be used as general I/O. Immediately following Table 14, see Table 15 for Differential Pair information.

Table 14: **BG560 — XCV400E, XCV600E, XCV1000E, XCV1600E, XCV2000E**

Bank	Pin Description	Pin#	See Note
0	GCK3	A17	
0	IO	A27	
0	IO	B25	
0	IO	C28	
0	IO	C30	
0	IO	D30	
0	IO_L0N	E28	
0	IO_VREF_L0P	D29	3
0	IO_L1N_YY	D28	
0	IO_L1P_YY	A31	
0	IO_VREF_L2N_YY	E27	
0	IO_L2P_YY	C29	
0	IO_L3N_Y	B30	
0	IO_L3P_Y	D27	
0	IO_L4N_YY	E26	
0	IO_L4P_YY	B29	
0	IO_VREF_L5N_YY	D26	
0	IO_L5P_YY	C27	
0	IO_L6N_Y	E25	
0	IO_VREF_L6P_Y	A28	1
0	IO_L7N_Y	D25	
0	IO_L7P_Y	C26	
0	IO_VREF_L8N_Y	E24	4
0	IO_L8P_Y	B26	
0	IO_L9N_Y	C25	
0	IO_L9P_Y	D24	
0	IO_VREF_L10N_YY	E23	
0	IO_L10P_YY	A25	
0	IO_L11N_YY	D23	

Table 20: **FG676 — XCV400E, XCV600E**

Bank	Pin Description	Pin #
1	IO_L40P_YY	D20
1	IO_L41N_YY	F19
1	IO_VREF_L41P_YY	C21
1	IO_L42N_YY	B22
1	IO_L42P_YY	E20
1	IO_L43N_Y	A23
1	IO_L43P_Y	D21
1	IO_WRITE_L44N_YY	C22
1	IO_CS_L44P_YY	E21
2	IO	D25[1]
2	IO	D26
2	IO	E26
2	IO	F26
2	IO	H26[1]
2	IO	K26[1]
2	IO	M25[1]
2	IO	N26[1]
2	IO_D1	K24
2	IO_DOUT_BUSY_L45P_YY	E23
2	IO_DIN_D0_L45N_YY	F22
2	IO_L46P_YY	E24
2	IO_L46N_YY	F20
2	IO_L47P_Y	G21
2	IO_L47N_Y	G22
2	IO_VREF_L48P_Y	F24
2	IO_L48N_Y	H20
2	IO_L49P_Y	E25
2	IO_L49N_Y	H21
2	IO_L50P_YY	F23
2	IO_L50N_YY	G23
2	IO_VREF_L51P_YY	H23
2	IO_L51N_YY	J20
2	IO_L52P_YY	G24
2	IO_L52N_YY	H22
2	IO_L53P_Y	J21
2	IO_L53N_Y	G25
2	IO_VREF_L54P_Y	G26[2]
2	IO_L54N_Y	J22
2	IO_L55P_YY	H24
2	IO_L55N_YY	J23
2	IO_L56P_YY	J24
2	IO_VREF_L56N_YY	K20
2	IO_D2_L57P_YY	K22
2	IO_L57N_YY	K21
2	IO_L58P_YY	H25
2	IO_L58N_YY	K23
2	IO_L59P_Y	L20
2	IO_L59N_Y	J26
2	IO_L60P_Y	K25
2	IO_L60N_Y	L22
2	IO_L61P_Y	L21
2	IO_L61N_Y	L23
2	IO_L62P_Y	M20
2	IO_L62N_Y	L24
2	IO_VREF_L63P_YY	M23
2	IO_D3_L63N_YY	M22
2	IO_L64P_YY	L26
2	IO_L64N_YY	M21
2	IO_L65P_Y	N19
2	IO_L65N_Y	M24
2	IO_VREF_L66P_Y	M26
2	IO_L66N_Y	N20
2	IO_L67P_YY	N24
2	IO_L67N_YY	N21
2	IO_L68P_YY	N23
2	IO_L68N_YY	N22
3	IO	P24
3	IO	P26[1]
3	IO	R26[1]
3	IO	T26[1]
3	IO	U26[1]
3	IO	W25

Table 20: **FG676 — XCV400E, XCV600E**

Bank	Pin Description	Pin #
7	IO	D2
7	IO	D3
7	IO	E1
7	IO	G1
7	IO	H2
7	IO	J1[1]
7	IO	L1[1]
7	IO	M1[1]
7	IO	N1[1]
7	IO_L160N_YY	N5
7	IO_L160P_YY	N8
7	IO_L161N_YY	N6
7	IO_L161P_YY	N3
7	IO_L162N_Y	N4
7	IO_VREF_L162P_Y	M2
7	IO_L163N_Y	N7
7	IO_L163P_Y	M7
7	IO_L164N_YY	M6
7	IO_L164P_YY	M3
7	IO_L165N_YY	M4
7	IO_VREF_L165P_YY	M5
7	IO_L166N_Y	L3
7	IO_L166P_Y	L7
7	IO_L167N_Y	L6
7	IO_L167P_Y	K2
7	IO_L168N_Y	L4
7	IO_L168P_Y	K1
7	IO_L169N_Y	K3
7	IO_L169P_Y	L5
7	IO_L170N_YY	K5
7	IO_L170P_YY	J3
7	IO_L171N_YY	K4
7	IO_L171P_YY	J4
7	IO_L172N_YY	H3
7	IO_VREF_L172P_YY	K6
7	IO_L173N_YY	K7
7	IO_L173P_YY	G3
7	IO_L174N_Y	J5
7	IO_VREF_L174P_Y	H1[2]
7	IO_L175N_Y	G2
7	IO_L175P_Y	J6
7	IO_L176N_YY	J7
7	IO_L176P_YY	F1
7	IO_L177N_YY	H4
7	IO_VREF_L177P_YY	G4
7	IO_L178N_Y	F3
7	IO_L178P_Y	H5
7	IO_L179N_Y	E2
7	IO_L179P_Y	H6
7	IO_L180N_Y	G5
7	IO_VREF_L180P_Y	F4
7	IO_L181N_Y	H7
7	IO_L181P_Y	G6
7	IO_L182N_YY	E3
7	IO_L182P_YY	E4
2	CCLK	D24
3	DONE	AB21
NA	DXN	AB7
NA	DXP	Y8
NA	M0	AD4
NA	M1	W7
NA	M2	AB6
NA	PROGRAM	AA22
NA	TCK	E6
NA	TDI	D22
2	TDO	C23
NA	TMS	F5
NA	NC	T25
NA	NC	T2
NA	NC	P2
NA	NC	N25
NA	NC	L25

Table 26: **FG900 — XCV600E, XCV1000E, XCV1600E**

Bank	Pin Description	Pin #
0	IO_L6N_Y	A5
0	IO_L6P_Y	F8
0	IO_L7N_Y	D7
0	IO_L7P_Y	N11
0	IO_L8N_YY	G9
0	IO_L8P_YY	E8
0	IO_VREF_L9N_YY	A6
0	IO_L9P_YY	J11
0	IO_L10N_Y	C7
0	IO_L10P_Y	B7
0	IO_L11N_Y	C8
0	IO_L11P_Y	H10
0	IO_L12N_YY	G10
0	IO_L12P_YY	F10
0	IO_VREF_L13N_YY	A8
0	IO_L13P_YY	H11
0	IO_L14N	D9[4]
0	IO_L14P	C9[3]
0	IO_L15N_YY	B9
0	IO_L15P_YY	J12
0	IO_L16N	E10[4]
0	IO_VREF_L16P	A9
0	IO_L17N	G11
0	IO_L17P	B10
0	IO_L18N_YY	H12[4]
0	IO_L18P_YY	C10[4]
0	IO_L19N_Y	H13
0	IO_L19P_Y	F11
0	IO_L20N_Y	E11
0	IO_L20P_Y	D11
0	IO_L21N_Y	B11[4]
0	IO_L21P_Y	G12[4]
0	IO_L22N_YY	F12
0	IO_L22P_YY	C11
0	IO_VREF_L23N_YY	A10[1]
0	IO_L23P_YY	D12
0	IO_L24N_Y	E12
0	IO_L24P_Y	A11
0	IO_L25N_Y	G13
0	IO_L25P_Y	B12
0	IO_L26N_YY	A12
0	IO_L26P_YY	K13
0	IO_VREF_L27N_YY	F13
0	IO_L27P_YY	B13
0	IO_L28N_Y	G14
0	IO_L28P_Y	E13
0	IO_L29N_Y	D14
0	IO_L29P_Y	B14
0	IO_L30N_YY	A14
0	IO_L30P_YY	J14
0	IO_VREF_L31N_YY	K14
0	IO_L31P_YY	J15
0	IO_L32N	B15[4]
0	IO_L32P	H15[3]
0	IO_VREF_L33N_YY	F15[2,3]
0	IO_L33P_YY	D15[4]
0	IO_LVDS_DLL_L34N	A15
1	GCK2	E15
1	IO	A25[4]
1	IO	B17[4]
1	IO	B18[4]
1	IO	C23[4]
1	IO	D16[4]
1	IO	D17[5]
1	IO	D23[4]
1	IO	E19[4]
1	IO	E24[5]
1	IO	F22[4]
1	IO	G17[5]
1	IO	G20[4]
1	IO	J16[4]
1	IO	J17[4]
1	IO	J19[5]

Table 26: **FG900 — XCV600E, XCV1000E, XCV1600E**

Bank	Pin Description	Pin #
3	IO_L127P_YY	Y24
3	IO_VREF_L127N_YY	AB28
3	IO_L128P_YY	AC30
3	IO_L128N_YY	AA25
3	IO_L129P	W21
3	IO_L129N	AA24
3	IO_L130P_YY	AB26
3	IO_L130N_YY	AD30
3	IO_L131P_YY	Y22
3	IO_VREF_L131N_YY	AC27
3	IO_L132P	AD28
3	IO_L132N	AB25
3	IO_L133P_YY	AC26
3	IO_L133N_YY	AE30
3	IO_L134P_YY	AD27
3	IO_L134N_YY	AF30
3	IO_L135P	AF29
3	IO_VREF_L135N	AB24
3	IO_L136P_YY	AB23
3	IO_L136N_YY	AE28
3	IO_L137P_Y	AG30[3]
3	IO_L137N_Y	AC25[4]
3	IO_L138P_YY	AE26
3	IO_VREF_L138N_YY	AG29[1]
3	IO_L139P	AH30
3	IO_L139N	AC24
3	IO_L140P	AF28[3]
3	IO_L140N	AD25[4]
3	IO_D7_L141P_YY	AH29
3	IO_INIT_L141N_YY	AA22
4	GCK0	AJ16
4	IO	AB19[4]
4	IO	AC16[4]
4	IO	AC19
4	IO	AD18[4]
4	IO	AD21[4]
4	IO	AE15[4]
4	IO	AE18[4]
4	IO	AE21
4	IO	AE24[5]
4	IO	AF17[5]
4	IO	AF18[5]
4	IO	AJ18[4]
4	IO	AK18
4	IO	AK25[5]
4	IO	AK27[4]
4	IO	AH23[4]
4	IO	AH24[5]
4	IO_L142P_YY	AF27
4	IO_L142N_YY	AK28
4	IO_L143P_YY	AG26[4]
4	IO_L143N_YY	AH27[3]
4	IO_L144P	AD23
4	IO_L144N	AJ27
4	IO_VREF_L145P	AB21[1]
4	IO_L145N	AF25
4	IO_L146P	AC22[4]
4	IO_L146N	AH26[4]
4	IO_L147P_YY	AA21
4	IO_L147N_YY	AG25
4	IO_VREF_L148P_YY	AJ26
4	IO_L148N_YY	AD22
4	IO_L149P	AA20
4	IO_L149N	AH25
4	IO_L150P	AC21
4	IO_L150N	AF24
4	IO_L151P_YY	AG24
4	IO_L151N_YY	AK26
4	IO_VREF_L152P_YY	AJ24
4	IO_L152N_YY	AF23
4	IO_L153P	AE23
4	IO_L153N	AB20
4	IO_L154P	AC20